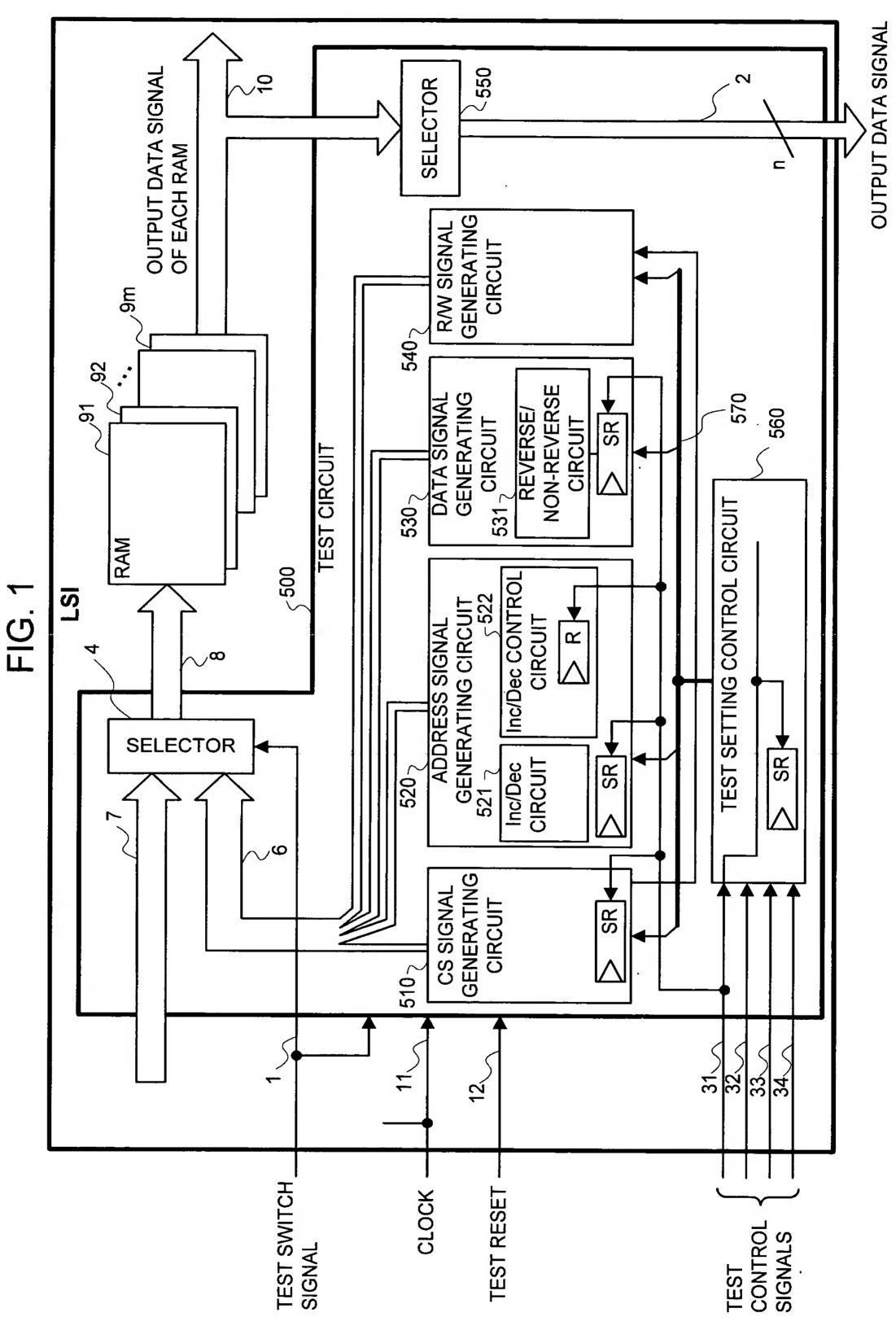
Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143



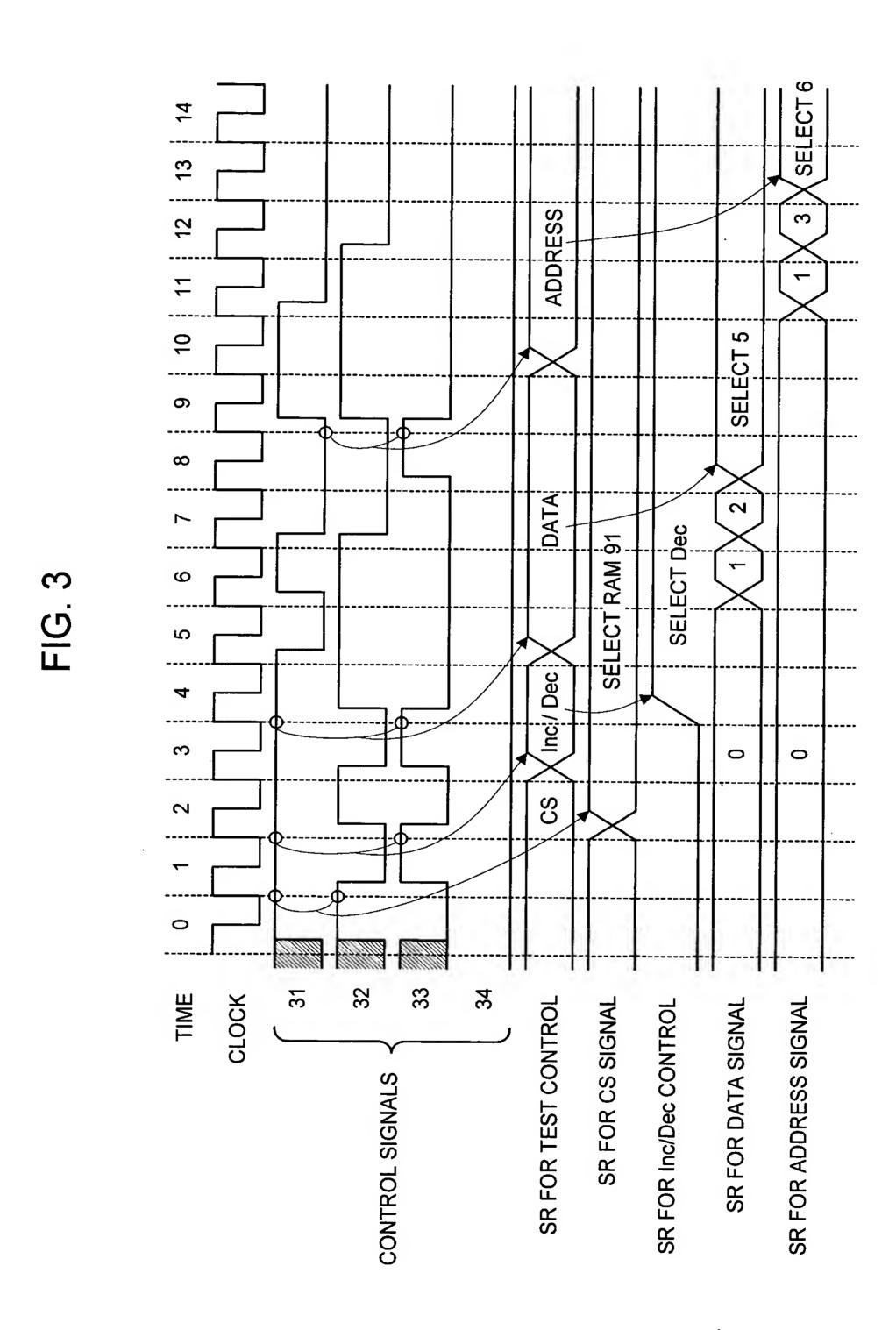
MEMORY

Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143

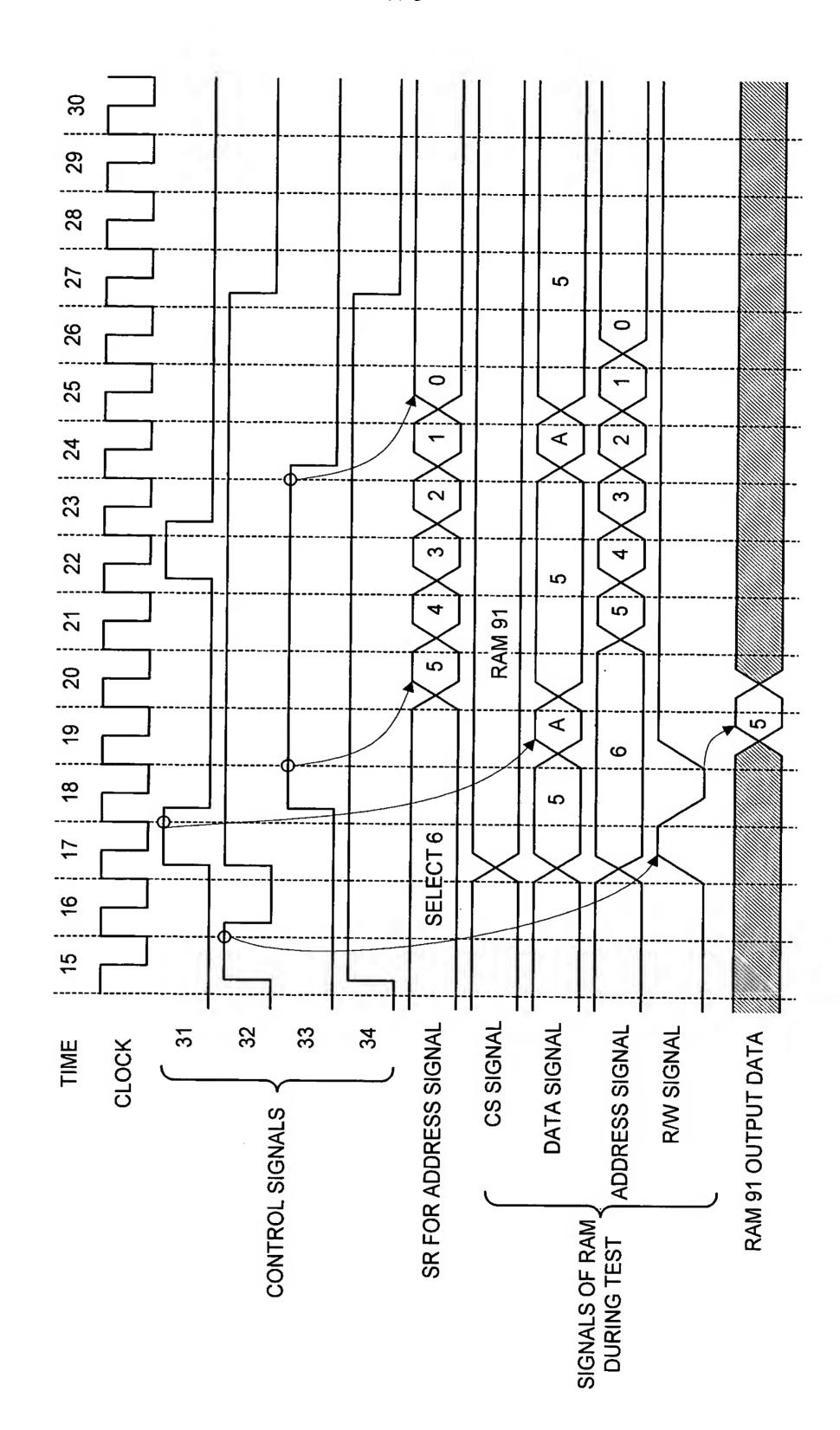
00	CONTROL	L SIGNAL	NAL		
34	33	32	31		O NO
	0	0	0		NO OPERATION
	0	0	_		RESERVED
0	0	~	×	TEST SETTING	SHIFT SR OF SIGNAL GENERATING CIRCUITS 510-530 AND Inc/Dec CONTROL CIRCUIT 522. INPUT IS CONTROL SIGNAL 31.
	_	0	×		SHIFT SR OF TEST SETTING CONTROL CIRCUIT 560. INPUT IS CONTROL SIGNAL 31.
	~	-	×		RESERVED
	0/1	×	×		CONTROL OF PRESENCE OR ABSENCE OF ADDRESS Inc(Dec). 1: PRESENCE 0: ABSENCE
←.	×	0/1	×	TEST EXECUTION	CONTROL OF R/W. 1: W(WRITE) 0: R(READ)
	×	×	0/1		CONTROL OF PRESENCE OR ABSENCE OF DATA REVERSE. 1: REVERSE 0: NON-REVERSE

FIG. 2

Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143



Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143



Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143

FIG. 5

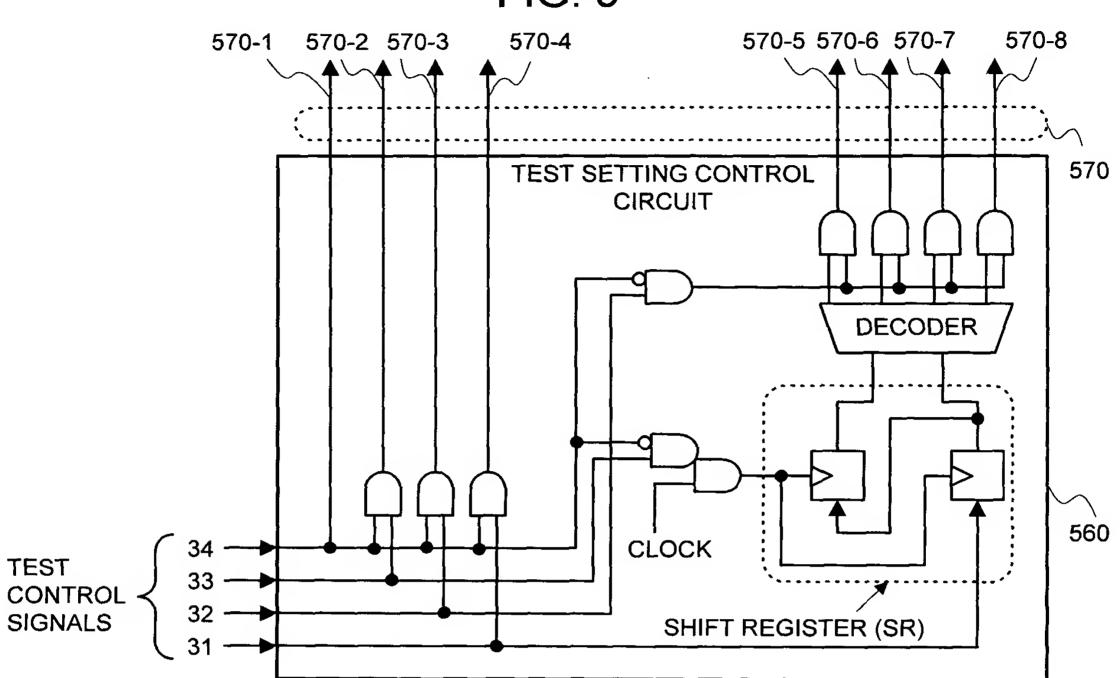
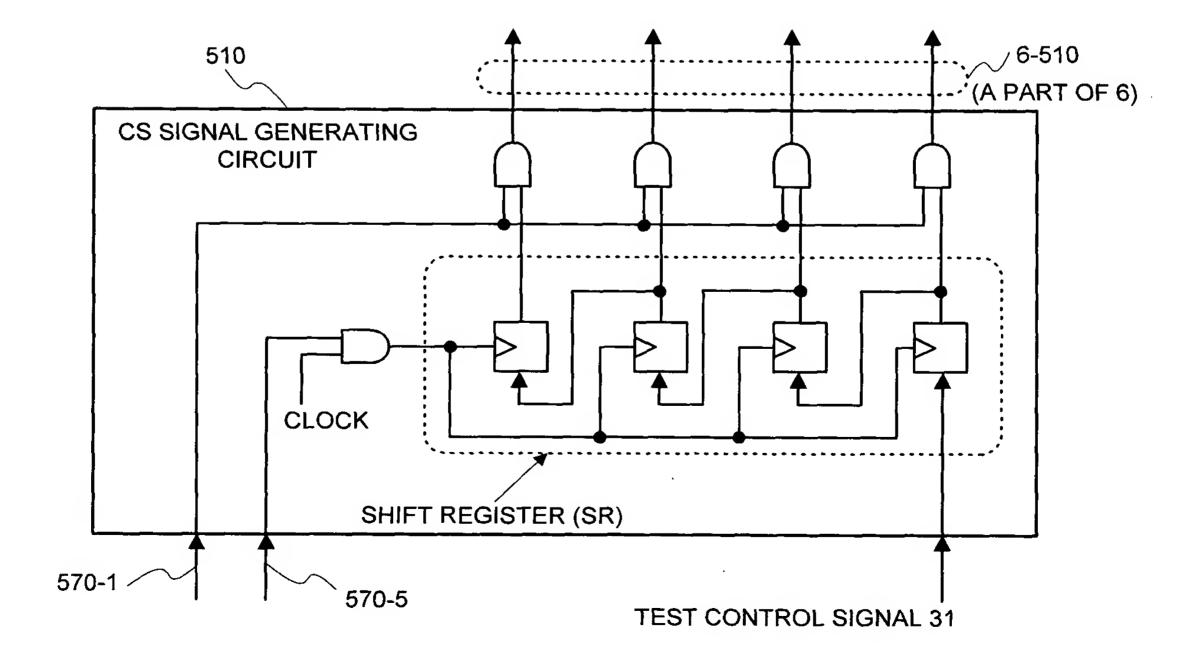


FIG. 6



Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143

FIG. 7

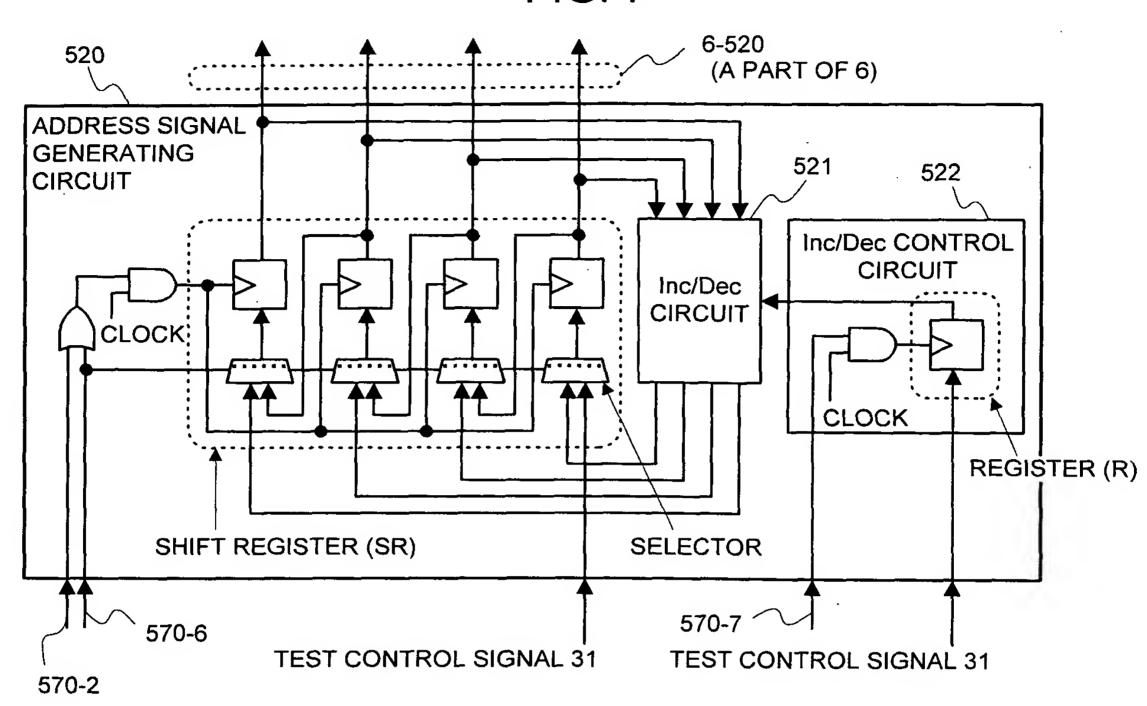
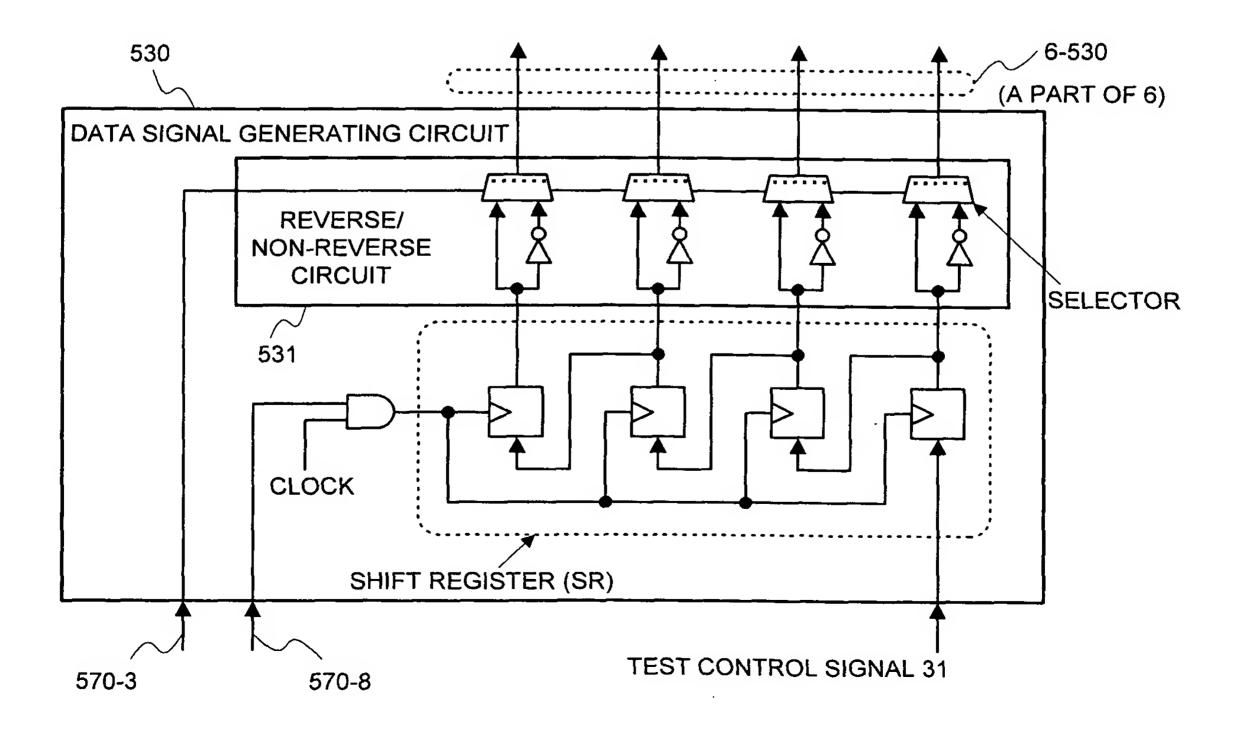


FIG. 8



Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143

FIG. 9

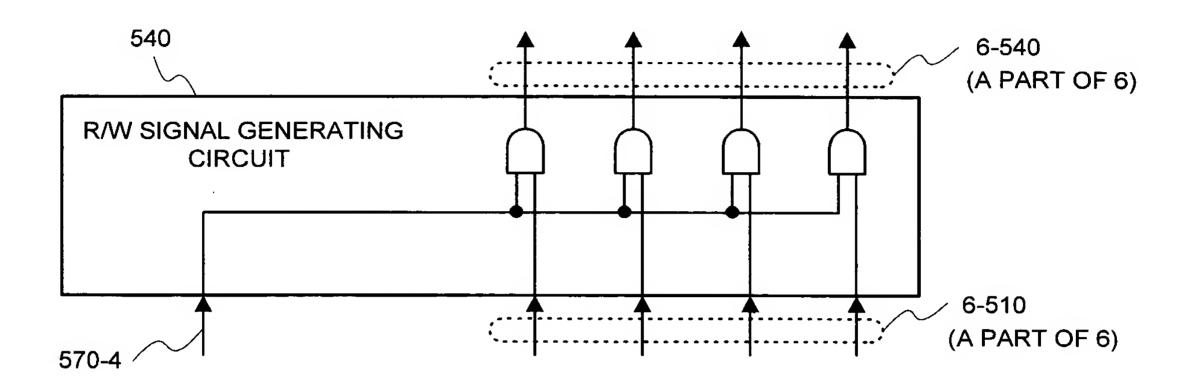
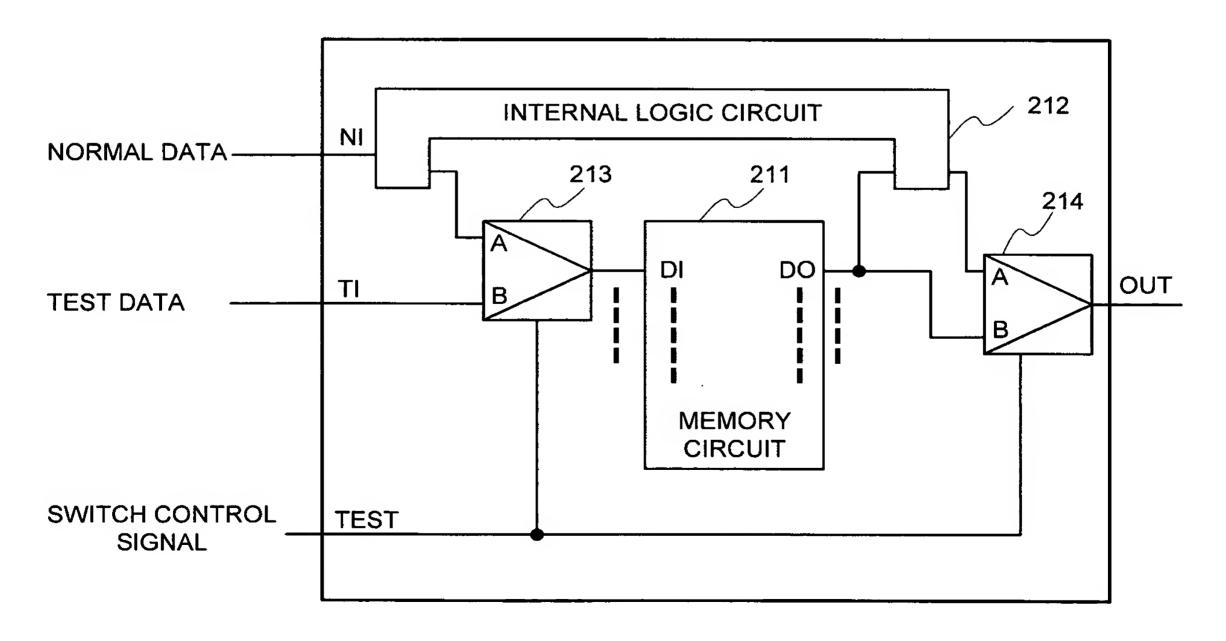


FIG. 10 PRIOR ART



Title: TEST CIRCUIT FOR **MEMORY** Inventor(s): Tatsuya KAWASAKI DOCKET NO.: 070639-0143 8/8 RAM TO BE TESTED SELECTOR TEST RESULT ANALYZER TEST PATTERN GENERATOR 110 115 109 108 107 MEMORY FOR RAM TEST COMMAND RAM TEST CONTROL CIRCUIT 103

106

TEST

FIG. 11 PRIOR ART

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